Advances and Applications of Computer Vision in Electronics

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Message from the Guest Editors

Dear Colleagues,

Recently, deep learning has achieved remarkable results in various applications. In particular, computer vision technologies using deep learning have achieved rapid technological improvement by overcoming various problems that conventional computer vision methods have found difficult or not solved.

Computer vision technologies are expanding from neural architecture research, such as a vision transformer, to 3D computer graphics, such as neural radiance fields. Therefore, this Special Issue aims to provide a unique academic platform for publishing high-quality papers dealing with advances and applications of computer vision technology in electronics. Contributors may write about one of the subjects listed below, but they are not limited to them.

- Machine Learning-based Computer Vision
- Deep Learning-based Computer Vision
- Efficient Computer Vision on Edge Devices
- Data Processing for Computer Vision
- 3D Computer Vision
- Applications (Autonomous Vehicles, Metaverse, Smart Factory, 3D Rendering, etc.)

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Special Issue

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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